In the Claims:

Claims 1-24 (Cancelled).

25. (Previously Added) A process for fabricating an integrated circuit comprising:

forming a gate on a silicon substrate;

amorphizing regions of the silicon substrate to obtain amorphous silicon regions adjacent the gate;

implanting dopants in the amorphous silicon regions to form drain and source extensions therein; and

forming drain and source regions in the respective drain and source extensions with a channel being defined therebetween, the drain and source regions being formed at a temperature below 800°C.

26. (Previously Added) A process according to Claim 25, wherein the silicon substrate comprises a crystalline silicon substrate.

27. (Previously Added) A process according to Claim 25, further comprising forming spacers on the silicon substrate adjacent the gate after forming the drain and source extensions.

28. (Previously Added) A process according to Claim 25, further comprising annealing the silicon substrate at a temperature below 800°C after forming the drain and source extensions.

29. (Previously Added) A process according to Claim 25, wherein implanting the dopants to form the drain and source extensions comprises performing a deep amorphization in the silicon substrate.

30. (Previously Added) A process according to Claim 29, further comprising recrystallizing the silicon substrate after performing the deep amorphorization.

31. (Previously Added) A process according to Claim 25, wherein forming the drain and source regions comprises implanting dopants therein.

32. (Previously Added) A process according to Claim 31, further comprising recrystallizing the silicon substrate after forming the drain and source regions.

33. (Previously Added) A process according to Claim 27, wherein forming the spacers comprises annealing the silicon substrate at a temperature below 800°C.

34. (Previously Added) A process according to Claim 27, further comprising annealing the silicon substrate after forming the spacers.

35. (Previously Added) A process according to Claim 25, further comprising forming pockets in the silicon substrate, the pockets being doped with a dopant having an

opposite conductivity to the dopant implanted when forming the drain and source regions.

36. (Previously Added) A process according to Claim 35, wherein the pockets are formed before the amorphized regions are formed.

37. (Previously Added) A process according to Claim 35, wherein the pockets are formed after the amorphized regions are formed.

38. (Previously Added) A process according to Claim 36, wherein the pockets are formed before the amorphized regions are formed, and before the dopants are implanted in the silicon substrate.

39. (Previously Added) A process according to Claim 27, wherein the spacers are formed after forming the drain and source extensions.

40. (Previously Added) A process according to Claim 27, wherein the spacers are formed before the amorphized regions are formed.

41. (Previously Added) A process according to Claim 25, wherein the amorphized regions have a thickness that is greater than 100 nanometers.

42. (Previously Added) A process according to Claim 25, wherein the source and drain extensions are formed after amorphizing the silicon substrate.

43. (Previously Added) A process according to Claim 25, wherein the source and drain regions are formed by annealing the silicon substrate at a temperature below 800°C.

44. (Previously Added) A process according to Claim 25, wherein amorphizing the regions of the silicon substrate comprises implanting ions therein.

45. (Previously Added) A process according to Claim 41, wherein the ions comprise at least one of silicon, germanium, argon, neon, zenon and krypton.

46. (Previously Added) A process according to Claim 25, wherein the dopants being implanted to form the drain and source extensions comprise at least one of B^+, BF_2^+, In^+, As^+, P^+ and Sb^+.

47. (Previously Added) An integrated circuit comprising:

a silicon substrate; and

at least one transistor in said silicon substrate and comprising

a gate on said silicon substrate,

amorphous silicon regions in said silicon substrate adjacent said gate, and

drain and source regions in said amorphous silicon regions and in said silicon substrate with a channel defined therebetween, the drain and source regions being formed at a temperature below 800°C.

48. (Previously Added) An integrated circuit according to Claim 47, wherein a length of said gate is less than 180 nanometers.

49. (Previously Added) An integrated circuit according to Claim 47, wherein a length of said gate is less than 100 nanometers.

50. (Previously Added) An integrated circuit according to Claim 47, wherein said silicon substrate comprises a crystalline silicon substrate.

51. (Previously Added) An integrated circuit according to Claim 47, further comprising pockets in said silicon substrate underlying said gate, said pockets being doped with dopants having an opposite conductivity to dopants in said drain and source regions.

52. (Previously Added) An integrated circuit according to Claim 47, wherein said amorphized silicon regions have a thickness that is greater than 100 nanometers.

53. (Previously Added) An integrated circuit according to Claim 47, wherein said amorphized silicon regions

comprise ions implanted therein, the ions comprising at least one of silicon, germanium, argon, neon, zenon and krypton.

54. (New) A process for fabricating an integrated circuit comprising:

forming a gate on a silicon substrate;

amorphizing regions of the silicon substrate to obtain amorphous silicon regions adjacent the gate;

implanting dopants in the amorphous silicon regions to form drain and source extensions therein; and

forming drain and source regions in the respective drain and source extensions with a channel being defined therebetween, the drain and source regions being formed at a relatively low temperature to avoid diffusion of the dopants from the drain and source extensions.

55. (New) A process according to Claim 54, wherein the temperature is within a range of 650 to 800°C.

56. (New) A process according to Claim 54, wherein the silicon substrate comprises a crystalline silicon substrate.

57. (New) A process according to Claim 54, further comprising forming spacers on the silicon substrate adjacent the gate after forming the drain and source extensions; and annealing the silicon substrate after forming the spacers.

58. (New) A process according to Claim 54, wherein

implanting the dopants to form the drain and source extensions comprises performing a deep amorphization in the silicon substrate; and further comprising recrystallizing the silicon substrate after performing the deep amorphorization.

59. (New) A process according to Claim 54, wherein forming the drain and source regions comprises implanting dopants therein; and further comprising recrystallizing the silicon substrate after forming the drain and source regions.

60. (New) A process according to Claim 54, further comprising forming pockets in the silicon substrate, the pockets being doped with a dopant having an opposite conductivity to the dopant implanted when forming the drain and source regions.

61. (New) A process according to Claim 54, wherein the amorphized regions have a thickness that is greater than 100 nanometers.

62. (New) A process according to Claim 54, wherein amorphizing the regions of the silicon substrate comprises implanting ions therein.